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| APPLICATION NO.   | FILING DATE    | FIRST NAMED INVENTOR  | ATTORNEY DOCKET NO.    | CONFIRMATION NO. |
|---|----------------|-----------------------|------------------------|------------------|
| 09/891,325  | 06/27/2001     | Osamu Samuel Nakagawa | 10005208-1             | 3642             |
| 7:  | 590 04/18/2005 |                       | EXAM                   | INER             |
| HEWLETT-PACKARD COMPANY                                 |                |                       | LUU, CHUONG A          |                  |
| Intellectual Property Administration<br>P.O. Box 272400 |                |                       | ART UNIT               | PAPER NUMBER     |
|   | O 80527-2400   |                       | 2818                   |                  |
|   |                |                       | DATE MAILED: 04/18/200 | 5                |

Please find below and/or attached an Office communication concerning this application or proceeding.

|   |  |   | Ale                    |  |
|---|--|---|------------------------|--|
|   | Application No.  | Applicant(s)  |                        |  |
|   | 09/891,325   | NAKAGAWA, OSAMU SA  | NAKAGAWA, OSAMU SAMUEL |  |
| Office Action Summary   | Examiner   | Art Unit  |                        |  |
|   | Chuong A. Luu  | 2818  |                        |  |
| The MAILING DATE of this communication app<br>Period for Reply  | pears on the cover sheet w   | ith the correspondence address  |                        |  |
| A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above, the maximum statutory period of the period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailine earned patent term adjustment. See 37 CFR 1.704(b). | 136(a). In no event, however, may a<br>ly within the statutory minimum of thi<br>will apply and will expire SIX (6) MO<br>e, cause the application to become A | reply be timely filed<br>ty (30) days will be considered timely.<br>NTHS from the mailing date of this communication<br>BANDONED (35 U.S.C. § 133). | on.                    |  |
| Status  |  |   |                        |  |
| 1) Responsive to communication(s) filed on Janu   | <u>iary 18, 2005</u> .   |   |                        |  |
| 2a) ☐ This action is <b>FINAL</b> . 2b) ☑ This  | s action is non-final.   |   |                        |  |
| 3) Since this application is in condition for allowa  | •  | ·   | is                     |  |
| closed in accordance with the practice under E  | Ex parte Quayle, 1935 C.I  | D. 11, 453 O.G. 213.  |                        |  |
| Disposition of Claims   | •  |   |                        |  |
| 4) ☐ Claim(s) 1-11 is/are pending in the application 4a) Of the above claim(s) is/are withdra  5) ☐ Claim(s) is/are allowed.  6) ☐ Claim(s) 1-11 is/are rejected.  7) ☐ Claim(s) is/are objected to.  8) ☐ Claim(s) are subject to restriction and/or   | wn from consideration.   |   |                        |  |
| Application Papers  |  |   |                        |  |
| 9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine 11.  | epted or b) objected to<br>drawing(s) be held in abeya<br>tion is required if the drawing  | nce. See 37 CFR 1.85(a).<br>(s) is objected to. See 37 CFR 1.121  | (d).                   |  |
| Priority under 35 U.S.C. § 119  |  |   |                        |  |
| 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Bureat * See the attached detailed Office action for a list  | ts have been received.  Is have been received in A  Inity documents have been  In (PCT Rule 17.2(a)).  | Application No  received in this National Stage   |                        |  |
| Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date  | Paper No   | Summary (PTO-413)<br>s)/Mail Date<br>nformal Patent Application (PTO-152)   |                        |  |

U.S. Patent and Trademark Office PTOL-326 (Rev. 1-04)

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#### **DETAILED ACTION**

## Response to Arguments

Applicant's arguments with respect to claims 1-11 have been considered but are moot in view of the new ground(s) of rejection.

### **PRIOR ART REJECTIONS**

# **Statutory Basis**

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

#### The Rejections

Claims 1-3, 5 and 7 are rejected under 35 U.S.C. 102(e) as being anticipated by Johnson et al. (U.S. 6,034,882).

Johnson discloses a very high density field programmable memory with Respect to claims:

(1) a first electrode (20) formed during a first deposition of a first metal layer of a multi-level semiconductor device;

a substantially thin dielectric layer (22, 23) configured to be deposited over said first electrode (20);

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a second electrode (21) formed during a second deposition of a second metal layer of said multi-level deposition device, wherein said second electrode (20) is formed over said substantially thin dielectric layer (22, 23), wherein said on-chip capacitor is formed in a crossover area of said first metal layer (20) and said second metal layer (21) of said multi-level semiconductor device (see column 10, lines 39-67; column 14, lines 59-65. Figure 4(a));

- (2) wherein an angle of intersection between said first metal layer (12) and said second metal layer (16) is between zero and ninety degrees (see column 10, lines 50-51. Figure 4(a));
- (3) wherein said first electrode and said second electrode are configured to be substantially parallel (see column 10, lines 56-58);
- (5) wherein said first electrode and said second electrode are configured as a rectangular planar structure (see column 10, lines 39-67. Figure 4(a));
- (7) wherein said substantially thin dielectric material comprises a composite of materials (see Figure 4(a));

Regarding the process limitations recited in claims 1-11 (first and second electrode are formed...), these would not carry patentable weight in this claim drawn to a structure, because distinct structure is not necessarily produced.

Note that a "product by process" claim is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17 (footnote 3). See also In re Brown, 173 USPQ 685; In re Luck, 177 USPQ 523; In re Fessmann, 180 USPQ 324; In re Avery, 186 USPQ 161; In re Wertheim, 191 USPQ 90 (209 USPQ 554 does not deal

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with this issue); and In re Marosi et al., 218 USPQ 289; and particularly In re Thorpe, 227 USPQ 964 (Fed. Cir. 1985), all of which make it clear that it is the patentability of the final product per se which must be determined in a "product by process" claim, and not the patentability of the process, and that an old or obvious product produced by a new method is not patentable as a product, whether claimed in "product by process" claims or not. Note that the applicant has the burden of proof in such cases, as the above case law makes clear. See also MPEP 706.03(e).

#### PRIOR ART REJECTIONS

## Statutory Basis

# Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

#### The Rejections

Claims 4, 6 and 10-11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Johnson et al. (U.S. 6,034,882) in view of Johnson (U.S. 6,689,644 B2).

Johnson teaches everything above except for different configured shapes of the first and second electrodes such as overlapping; specific material and thickness of the thin dielectric layer. However, Johnson discloses a non-volatile memory device with (4)

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wherein said first electrode and said second electrode are further configured to be overlapping (see column 18, lines 50-51) (6) wherein said first electrode and said second electrode are substantially parallel and overlapping; (10) wherein said substantially thin dielectric material layer includes silicon nitride (see column 8, lines 60-61); (11) wherein said thickness of said substantially thin dielectric material layer is between 50 to 100 Å; (8) wherein said material comprises a composite of materials includes PZT and platinum; (9) wherein a dielectric constant of said substantially thin dielectric material layer is substantially high). It would have been obvious to one having ordinary skill in the art at the time the invention was made to combine the teachings of Johnson ('882) and Johnson ('644) to select specific structure configurations as well as material and thickness of the thin dielectric layer for a capacitor structure, since it has been held that the provision of adjustability, where needed, involves only routine skill in the art. In re Stevens, 101 USPQ 284 (CCPA 1954); In re Aller, 105 USPQP 233.

# Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Chuong A. Luu whose telephone number is (571) 272-1902. The examiner can normally be reached on M-F (6:15-2:45).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David C. Nelms can be reached on (571) 272-1787. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Chuong Anh Luu Patent Examiner April 14, 2005